



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-16

CB Certificate No.: 50600599 ITL

Schedule Number: IECQ-L ULTW 16.0003-16-S Rev No.: 1 Revision Date: 2024/09/03 Page 1 of 1

Appendix-1 (50600599 ITL)

Schedule of Scope to Certificate of Approval

| Tests | Standards/Procedures |
|---|----------------------|
| Scanning Electron Microscope (SEM) | T-SEM-3 |
| EMMI-InGaAs | T-EFA-3 |
| Focused Ion Beam Microscope (FIB) | T-FIB-3 |
| Optical Microscope (OM) | T-OMI-3 |
| 3D Optical Microscope | T-LAB-3 |
| Chemical Treatment | T-LAB-3 |
| 2D X-Ray imaging | T-EFA-3 |
| Optical Beam Induced Resistance Change (OBIRCH) | T-EFA-3 |
| Scanning Acoustic Tomography (SAT) | T-EFA-3 |
| THEMOS | T-EFA-3 |

Technical Reviewer of DQS: _____

Date: 9/3/2024

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